## XN09D58

# Silicon PNP epitaxial planar type (Tr) Silicon epitaxial planar type (SBD)

#### For DC-DC converter

#### ■ Features

- Two elements incorporated into one package (Tr + SBD)
- Reduction of the mounting area and assembly cost by one half
- Low collector-emitter saturation voltage V<sub>CE(sat)</sub>

#### ■ Basic Part Number

• XN9D57 + MA3ZD12

#### ■ Absolute Maximum Ratings $T_a = 25$ °C

	Parameter	Symbol	Rating	Unit	
Tr	Collector-base voltage (Emitter open)	V <sub>CBO</sub>	-15	V	
	Collector-emitter voltage (Base open)	V <sub>CEO</sub>	-15	V	
	Emitter-base voltage (Collector open)	V <sub>EBO</sub>	-5	V	
	Collector current	$I_{C}$	-2.5	A	
	Peak collector current	$I_{CP}$	-10	A	
SBD	Reverse voltage	V <sub>R</sub>	20	V	
	Repetitive peak reverse voltage	V <sub>RRM</sub>	25	V	
	Forward current (Average)	I <sub>F(AV)</sub>	700	mA	
	Non-repetitive peak forward surge current	$I_{FSM}$	2	A	
Overall	Total power dissipation *	$P_{T}$	600	mW	
	Junction temperature	$T_{j}$	125	°C	
	Storage temperature	T <sub>stg</sub>	-55 to +125	°C	

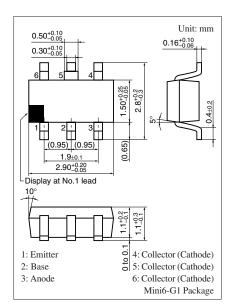


## ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

#### • Tr

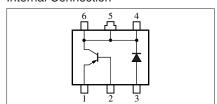
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	$I_C = -10 \ \mu A, I_E = 0$	-15			V
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_{\rm C} = -1  \text{mA},  I_{\rm B} = 0$	-15			V
Emitter-base voltage (Collector open)	$V_{EBO}$	$I_E = -10 \ \mu A, I_C = 0$	-5			V
Collector-base cutoff current (Emitter open)	$I_{CBO}$	$V_{CB} = -10 \text{ V}, I_E = 0$			- 0.1	μΑ
Forward current transfer ratio *	h <sub>FE1</sub>	$V_{CE} = -2 \text{ V}, I_{C} = -100 \text{ mA}$	200		560	_
	h <sub>FE2</sub>	$V_{CE} = -2 \text{ V}, I_{C} = -2.5 \text{ A}$	100			_
Collector-emitter saturation voltage *	V <sub>CE(sat)</sub>	$I_C = -1 \text{ A}, I_B = -10 \text{ mA}$		-140		mV
		$I_C = -2.5 \text{ A}, I_B = -50 \text{ mA}$		-270	-320	

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors. 2. \*: Pulse measurement



#### Marking Symbol: EF

#### Internal Connection



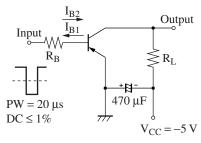
## ■ Electrical Characteristics (continued) $T_a = 25$ °C $\pm 3$ °C

#### • Tr (continued)

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		40		pF
(Common base, input open circuited)						
Transition frequency	$f_T$	$V_{CB} = -10 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		180		MHz
Turn-on time	t <sub>on</sub>	Refer to the switching time measurement circuit		35		ns
Storage time	t <sub>stg</sub>			110		ns
Turn-off time	t <sub>off</sub>			10		ns

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

#### Switching time measurement circuit



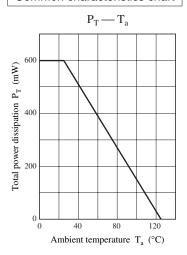
$$-20I_{B1} = 20I_{B2} = I_C = -1.5 A$$

#### • SBD

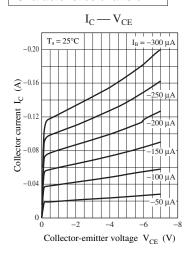
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Forward voltage	V <sub>F</sub>	$I_F = 700 \text{ mA}$			0.45	V
Reverse current	$I_R$	$V_R = 20 \text{ V}$			200	μΑ
Terminal capacitance	$C_{t}$	$V_R = 0$ , $f = 1$ MHz		100		pF
Reverse recovery time	t <sub>rr</sub>	$I_F = I_R = 100 \text{ mA}, I_{rr} = 10 \text{ mA}$		7		ns
		$R_L = 100 \Omega$				

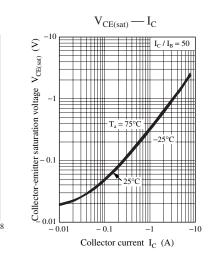
- Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7031 Measuring methods for diodes.
  - 2. Schottky barrier diode is frail with static electricity, and it should be kept in safety from shock of static electricity and static electricity level.

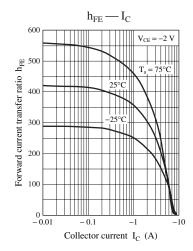
#### Common characteristics chart

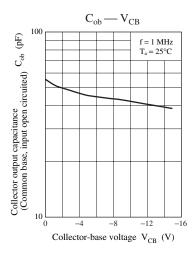


#### Characteristics charts of Tr

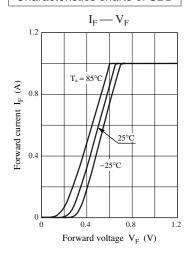


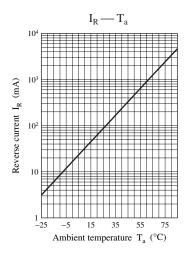


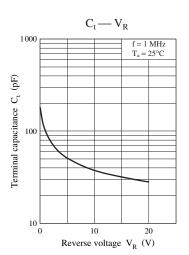




#### Characteristics charts of SBD







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